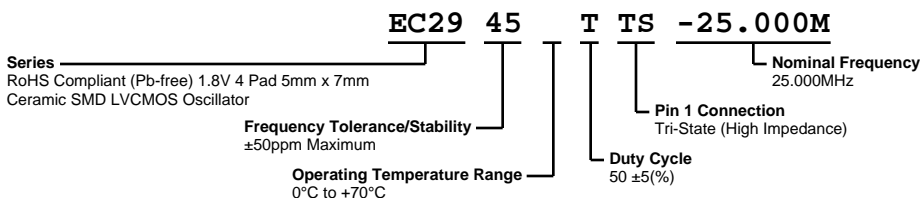


# EC2945TTS-25.000M



**ECLIPTEK**  
CORPORATION



## ELECTRICAL SPECIFICATIONS

Nominal Frequency	25.000MHz
Frequency Tolerance/Stability	±50ppm Maximum (Inclusive of all conditions: Calibration Tolerance at 25°C, Frequency Stability over the Operating Temperature Range, Supply Voltage Change, Output Load Change, First Year Aging at 25°C, Shock, and Vibration)
Operating Temperature Range	0°C to +70°C
Supply Voltage	1.8Vdc ±5%
Input Current	3mA Maximum
Output Voltage Logic High (Voh)	90% of Vdd Minimum (IOH=-2.8mA)
Output Voltage Logic Low (Vol)	10% of Vdd Maximum (IOL=2.8mA)
Rise/Fall Time	6nSec Maximum (Measured at 10% to 90% of waveform)
Duty Cycle	50 ±5(%) (Measured at 50% of waveform)
Load Drive Capability	15pF Maximum
Output Logic Type	CMOS
Pin 1 Connection	Tri-State (High Impedance)
Tri-State Input Voltage (Vih and Vil)	90% of Vdd Minimum to enable output, 10% of Vdd Maximum to disable output (High Impedance), No Connect to enable output.
Standby Current	10µA Maximum (Disabled Output, High Impedance) (Disabled Output, High Impedance)
RMS Phase Jitter	1pSec Maximum (12kHz to 20MHz offset frequency)
Start Up Time	10mSec Maximum
Storage Temperature Range	-55°C to +125°C

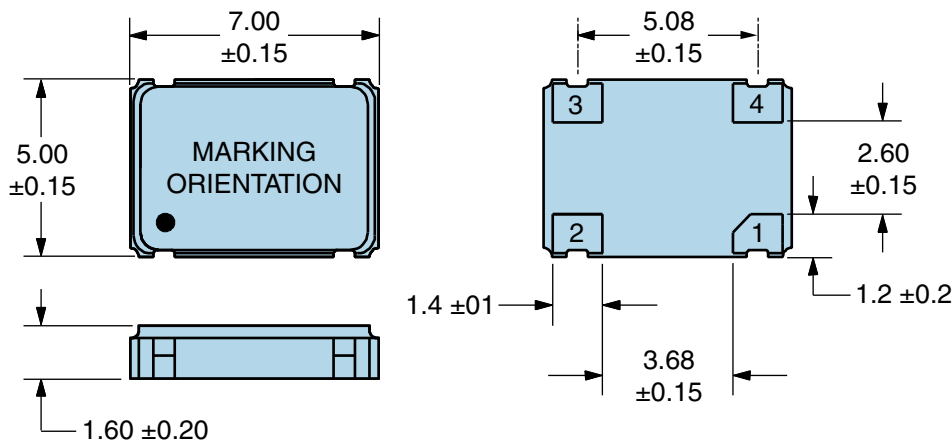
## ENVIRONMENTAL & MECHANICAL SPECIFICATIONS

Fine Leak Test	MIL-STD-883, Method 1014, Condition A
Gross Leak Test	MIL-STD-883, Method 1014, Condition C
Mechanical Shock	MIL-STD-202, Method 213, Condition C
Resistance to Soldering Heat	MIL-STD-202, Method 210
Resistance to Solvents	MIL-STD-202, Method 215
Solderability	MIL-STD-883, Method 2003
Temperature Cycling	MIL-STD-883, Method 1010
Vibration	MIL-STD-883, Method 2007, Condition A



# EC2945TTS-25.000M

## MECHANICAL DIMENSIONS (all dimensions in millimeters)

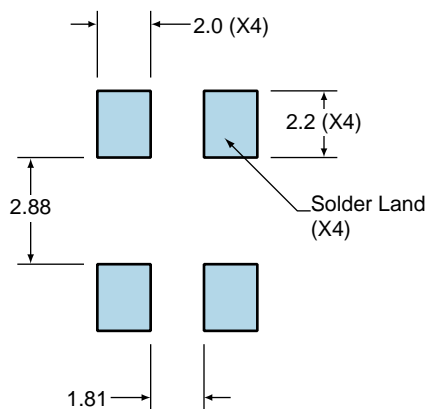


PIN	CONNECTION
1	Tri-State
2	Ground/Case Ground
3	Output
4	Supply Voltage

LINE	MARKING
1	<b>ECLIPTEK</b>
2	<b>25.000M</b>
3	<b>XXYYZZ</b> <i>XX=Ecliptek Manufacturing Code</i> <i>Y=Last Digit of the Year</i> <i>ZZ=Week of the Year</i>

## Suggested Solder Pad Layout

All Dimensions in Millimeters

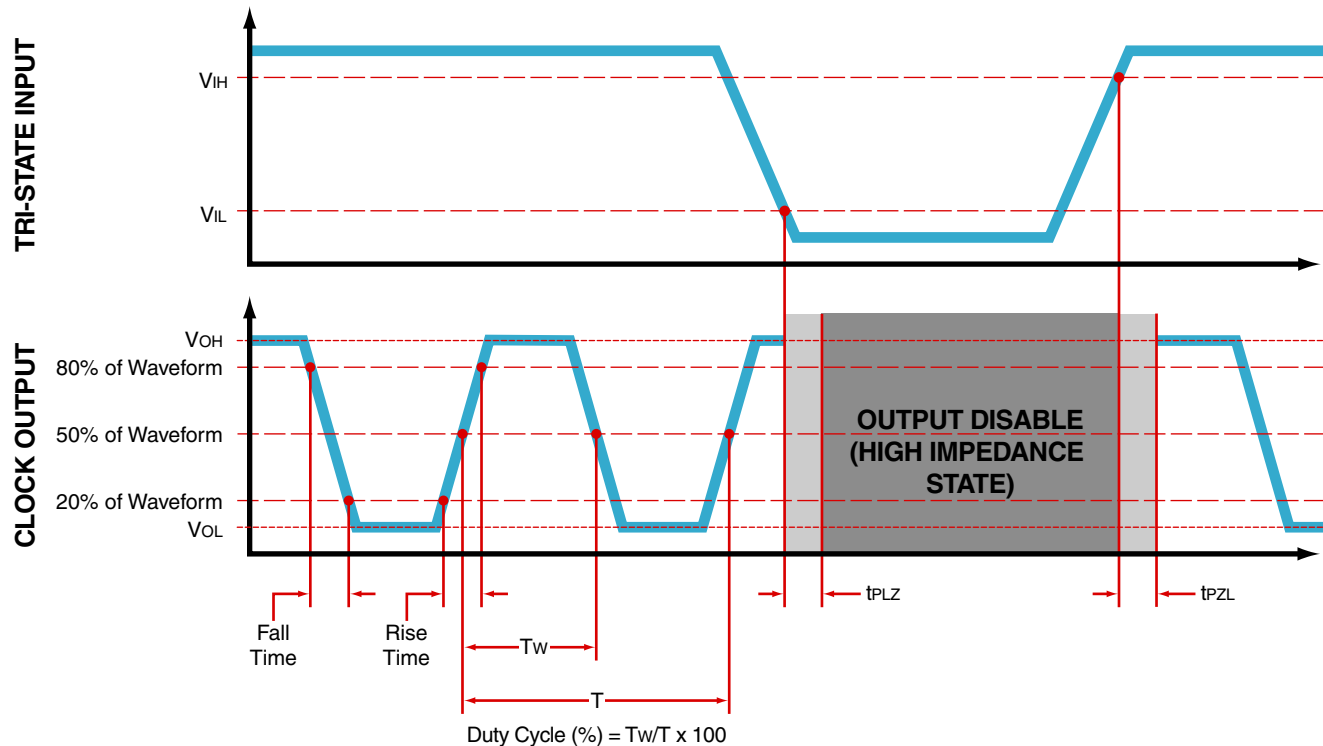


All Tolerances are ±0.1

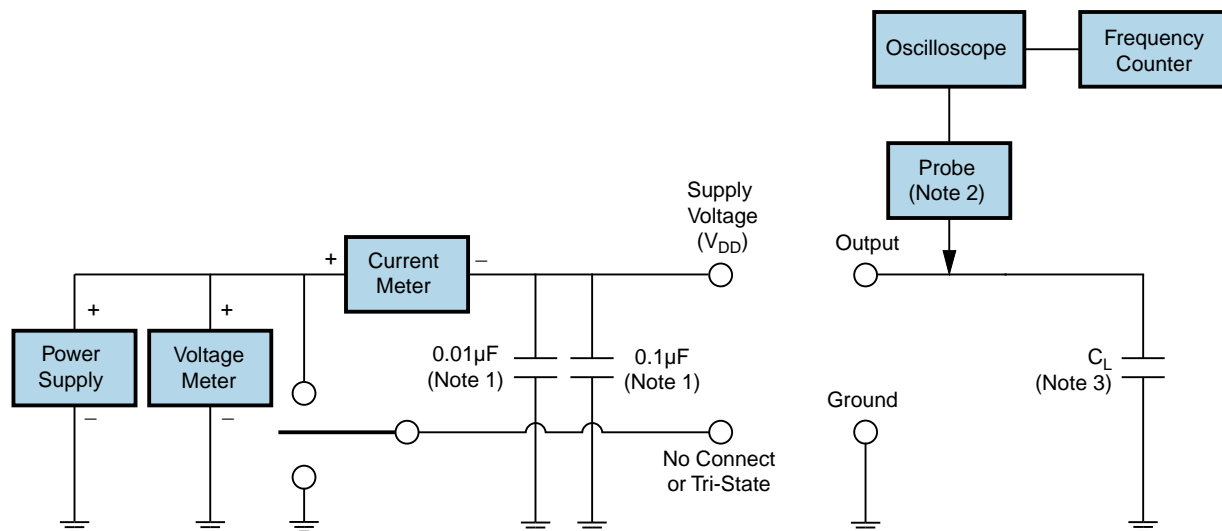


# EC2945TTS-25.000M

## OUTPUT WAVEFORM & TIMING DIAGRAM



## Test Circuit for CMOS Output



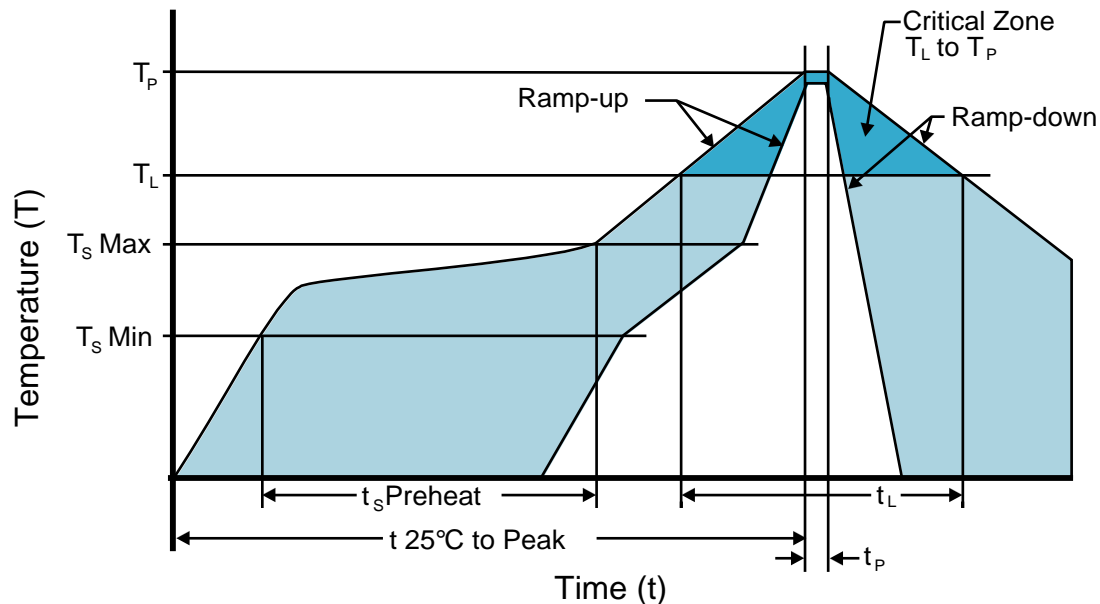
Note 1: An external 0.1 $\mu$ F low frequency tantalum bypass capacitor in parallel with a 0.01 $\mu$ F high frequency ceramic bypass capacitor close to the package ground and  $V_{DD}$  pin is required.

Note 2: A low capacitance (<12pF), 10X attenuation factor, high impedance (>10Mohms), and high bandwidth (>300MHz) passive probe is recommended.

Note 3: Capacitance value  $C_L$  includes sum of all probe and fixture capacitance.



## Recommended Solder Reflow Methods



### High Temperature Infrared/Convection

$T_s \text{ MAX to } T_L$ (Ramp-up Rate)	3°C/second Maximum
<b>Preheat</b>	
- Temperature Minimum ( $T_s \text{ MIN}$ )	150°C
- Temperature Typical ( $T_s \text{ TYP}$ )	175°C
- Temperature Maximum ( $T_s \text{ MAX}$ )	200°C
- Time ( $t_s \text{ MIN}$ )	60 - 180 Seconds
<b>Ramp-up Rate (<math>T_L</math> to <math>T_p</math>)</b>	3°C/second Maximum
<b>Time Maintained Above:</b>	
- Temperature ( $T_L$ )	217°C
- Time ( $t_L$ )	60 - 150 Seconds
<b>Peak Temperature (<math>T_p</math>)</b>	260°C Maximum for 10 Seconds Maximum
<b>Target Peak Temperature (<math>T_p \text{ Target}</math>)</b>	250°C +0/-5°C
<b>Time within 5°C of actual peak (<math>t_p</math>)</b>	20 - 40 seconds
<b>Ramp-down Rate</b>	6°C/second Maximum
<b>Time 25°C to Peak Temperature (t)</b>	8 minutes Maximum
<b>Moisture Sensitivity Level</b>	Level 1
<b>Additional Notes</b>	Temperatures shown are applied to body of device.



## Recommended Solder Reflow Methods



### Low Temperature Infrared/Convection 240°C

$T_S$ MAX to $T_L$ (Ramp-up Rate)	5°C/second Maximum
-----------------------------------	--------------------

#### Preheat

- Temperature Minimum ( $T_S$ MIN)	N/A
- Temperature Typical ( $T_S$ TYP)	150°C
- Temperature Maximum ( $T_S$ MAX)	N/A
- Time ( $t_s$ MIN)	60 - 120 Seconds

Ramp-up Rate ( $T_L$ to $T_P$ )	5°C/second Maximum
---------------------------------	--------------------

#### Time Maintained Above:

- Temperature ( $T_L$ )	150°C
- Time ( $t_L$ )	200 Seconds Maximum

Peak Temperature ( $T_P$ )	240°C Maximum
----------------------------	---------------

Target Peak Temperature ( $T_P$ Target)	240°C Maximum 1 Time / 230°C Maximum 2 Times
---	--

Time within 5°C of actual peak ( $t_p$ )	10 seconds Maximum 2 Times / 80 seconds Maximum 1 Time
--	--

Ramp-down Rate	5°C/second Maximum
----------------	--------------------

Time 25°C to Peak Temperature (t)	N/A
-----------------------------------	-----

Moisture Sensitivity Level	Level 1
----------------------------	---------

Additional Notes	Temperatures shown are applied to body of device.
------------------	---

### Low Temperature Manual Soldering

185°C Maximum for 10 seconds Maximum, 2 times Maximum. (Temperatures shown are applied to body of device.)

### High Temperature Manual Soldering

260°C Maximum for 5 seconds Maximum, 2 times Maximum. (Temperatures shown are applied to body of device.)